

Search Notes

Application/Control No.

09/764,787

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under
Reexamination

SCHWARTZ ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
III NPL (dialogs) 5/06 ZN		
1. Ftext 1		
2. Ftext 2		
3. Mtext		